### **Standard Delivery Specification For LCD Panels**

#### **Quality level**

#### **1.1 Inspection conditions**

1.1.1The environmental conditions for inspection shall be as follows Room temperature:  $22\pm5$  °C Humidity :  $65\pm20\%$  RH

1.1.2 The external visual inspection

The inspection shall be performed by using a single 20W fluorescent lamp for illumination and the distance from LCD to eyes of the inspector should be  $30\pm5$ cm.

#### 1.1.3 Light method



1.1.4 Inspection distance and angle



Inspection should be performed within  $\Phi(\Phi \text{ is usually } 30^\circ)$  from Z axis to each X and Y axis. Inspection distance of any direction within  $\Phi$  must be kept  $30\pm5$ cm to the display surface.

## 1.2 Sampling procedures for each item's acceptance level table

Defect type	Sampling procedures	AQL
Major defect	GB2828-87 single sampling plans for normal inspection.	0.65
Minor defect	GB2828-87 single sampling plans for normal inspection.	1.5

#### **1.3 Classification of defects**

#### 1.3.1 Major defect

A major defect refers to a defect that is considered to substantially degrade usability for product applications.

#### 1.3.2 Minor defect

A minor defect refers to a defect that is not considered to substantially degrade product application, or a defect that deviates from existing standards almost unrelated to the effective use of the product or its operation.

1.3.3 Defect application zone



#### **1.4 Inspection standards**

ITEM	Criterion for defects	Classification
		of defects
(1)Open segment and open	Any segment or common patterns that does not activate when they should are rejected.	Major
common		
(2)Short	. No shorts are allowed.	Major

	. Segment-to-segment shorts are when two or	
	more segment electrodes are bridged	
	together; they cause the shorted segment to	
	activate together when they should not.	
	(They may not be as dark as other segments)	
	. Segment-to-common shorts are caused by	
	some conductive foreign materials in the	
	fluid bridging between a segment and back	
	plane electrodes.	
(3)High	The total current required to activate all	Major
current	segments shall not exceed the limit specified	·
	in the specification for approval for the tested	
	voltage.	
(4)Weak	Segments that only partially activate are	Major
segment(Dim	rejected: they are not as dark as other	
segment)	segments	
(5)Display	(1)Dot type	Minor
Pattern	(1)Dot type	WIIIOI
1 uttern	ر م	
	В	
	Unit: mm	
	(A+B)/2 < 0.25 C > 0	
	$(D+E)/2 \le 0.25 \le 0.00$ $(D+E)/2 \le 0.25 (E+G)/2 \le 0.25$	
	(D+D)/2 = 0.25 $(1+O)/2 = 0.25$	
	1) Accentable up to 3 damages	
	2) If there're two or more ninholes per digit	
	2) If there is two of more printoles per digit,	
	11 IS Tejected.	
	2) Segment type:	
	· //	
	1 <del></del>	
	j.	
	·····································	
	$C \leq W/4  d \leq W/4$	
	Note:	
	1) Acceptable up to 3 damages.	
	2) If there're two or more pinholes per digit,	
	it is rejected.	

	Size D (mm)	Accept	Acceptable number					
	D=(a+b)/2	1	A zone					
	D < 0.15	]	gnore					
	0.15≤D < 0.2	5	2					
	0.18 < D < 0.2	25	1					
	0.25≤D		0					
(6)Blemishes		Accepta	cceptable number					
or Foreign	Size D (mm)	A zone	A zone B zone					
MattersSize: D = (A + B)/2	D≤0.15	Ignore	e Ignore					
D–(A+D)/2 B	0.15 < D≤0.20	) 2	I	gnor	e			
	0.2 < D≤0.25	1		-				
	0.2 < D≤0.3	-		2				
	0.25 < D≤0.3	0		1				
	0.5 < D	0		0				
(7)Dark lines and scratches	Width (mm)	Length(n	ength(mm) Acceptal numbe A B		ole r		Minor	
	W<0.03	I < 3 (	)	2011e	ZOI	le		
	₩ <u>~</u> 0.03	L <u>&lt;</u> 3.0	, )	2		ле		
	0.05 < W <u>-</u> 0.05	L <u>-</u> 2.0	)	1	2	, ,		
	0.08 <w<0.1< td=""><td>L&lt;3.0</td><td>)</td><td>0</td><td>- 1</td><td></td><td></td><td></td></w<0.1<>	L<3.0	)	0	- 1			
	0.1 <w< td=""><td>L&gt;3.0</td><td>)</td><td>0</td><td>0</td><td></td><td></td><td></td></w<>	L>3.0	)	0	0			
(8)Air bubble in	Size D (mm)	Accepta A zone	Acceptable : A zone B		ber e			Minor
polarizer	D≤0.20	Ignore	nore Ignore		e			
	0.20 < D≤0.40	) 3	I	Ignore				
	0.40 < D≤0.60	) 2	2 Ignore		e			
	0.2 < D≤0.3	0	0					
(9)Dirt	Products pass if the dirt can be wiped off easily							
(10)Chip in corner	I.T.D electrode							
	a l	b c	Ac n	cepta umb	able er			

	a < 4mm	b≤W	C≤T	3		
(11)Chip in seal area	VIEWING APEA					Minor
	а	b		c	Acceptable number	
	a < 3mm	b≤1.5n	nm c	≤1/2T	3	
	Chip is rejet the glass th damaged.					
(12)Chip in pad(1)	b c				Minor	
	а	b c	Ac n	ceptable umber	e	
	a≤2mm b≤	W/4 c≤]	Гi	gnore		
(13)Chip in	a≤3mm b≤	W/4 c≤]	Γ	3 b	1	Minor
pad(2)	No contraction of the second s	c,	¢.	P	X	
	а	b c	Ac n	ceptable umber	e	
	a≤2mm b≤	W/3 c≤]	Г i	gnore		
	a≤4mm b≤	W/2 c $\leq$	Γ	3		

(14)Chip in other sides			0			Minor
	а	b	c	Acceptable number		
	a≤3mm	b≤1mm	c≤T	ignore		
	a≤4mm	b≤1.5mm	c≤T	3		
(15)Glass rest		K	a<1/	W V 4W	]	Minor

# Reliability

**2.1 Items of reliability** All test result items should be judged after 4 hours recovery time at room temperature and under the state of not operating.

ITEM	Condition	Criterion
(1)High		Total current consumption should
temperature		be below double of initial
operating		value. Cosmetic defects should not
(2)Low		be happened.
temperature		
operating		
(3)Humidity	60±2°C 95±5%RH 96hours	
(without		
polarizer)		
(4)High	60°C 96hours	
temperature		
storage		
(5)Low	-10°C 24hours	
temperature		
storage		
(6)Thermal	-20°C→25°C→70°C	
shock storage	30min 5min 30min 5cycle	

(7)Vibration	50Hz	
	amplitude :0.7mm 30min for	
	each direction (X.Y.Z)	

Note: No cosmetic failure means there must be no permanent cosmetic defect and does not include any recoverable defect after 24 hours or more.